

# **FDH44N50**

# 44A, 500V, 0.12 Ohm, N-Channel SMPS Power MOSFET

### **Applications**

## Switch Mode Power Supplies(SMPS), such as

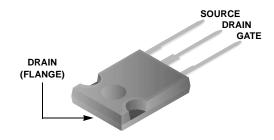
- PFC Boost
- Two-Switch Forward Converter
- Single Switch Forward Converter
- · Flyback Converter
- Buck Converter
- High Speed Switching

## **Features**

- ullet Low Gate Charge  $\mathbf{Q}_{\mathbf{g}}$  results in Simple Drive Requirement
- Improved Gate, Avalanche and High Reapplied dv/dt Ruggedness
- Reduced r<sub>DS(ON)</sub>
- Reduced Miller Capacitance and Low Input Capacitance
- · Improved Switching Speed with Low EMI
- 175°C Rated Junction Temperature

## **Package**

#### JEDEC TO-247



# **Symbol**



# **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	500	V
V <sub>GS</sub>	Gate to Source Voltage	±30	V
	Drain Current		
	Continuous ( $T_C = 25^{\circ}C$ , $V_{GS} = 10V$ )	44	А
I <sub>D</sub>	Continuous ( $T_C = 100^{\circ}C$ , $V_{GS} = 10V$ )	32	А
	Pulsed <sup>1</sup>	176	А
Ъ	Power dissipation	750	W
$P_{D}$	Derate above 25°C	5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to 175	°C
	Soldering Temperature for 10 seconds	300 (1.6mm from case)	°C
	Mounting Torque, 8-32 or M3 Screw	10ibf*in (1.1N*m)	

## **Thermal Characteristics**

$R_{ hetaJC}$	Thermal Resistance Junction to Case	0.2	°C/W
$R_{\theta CS}$	Thermal Resistance Case to Sink, Flat, Greased Surface	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	40	°C/W

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH44N50	FDH44N50	TO-247	-	-	30

# **Electrical Characteristics** $T_J = 25^{\circ}C$ (unless otherwise noted)

Symbol	Parameter	Test Con	ditions	Min	Тур	Max	Units
Statics							
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS}$	<sub>S</sub> = 0V	500	-	-	V
$\Delta B_{VDSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	Reference to 2 ID = 1mA	5°C,	-	0.61	-	V/°C
r <sub>DS(ON)</sub>	Drain to Source On-Resistance	$V_{GS} = 10V, I_D =$	22A	-	0.11	0.12	Ω
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D =$	250µA	2	3.15	4	V
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500V	$T_{\rm C} = 25^{\rm o}{\rm C}$	-	-	25	^
IDSS	Zero Gate voltage Dialii Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

## **Dynamics**

9 <sub>fs</sub>	Forward Transconductance	$V_{DS} = 50V, I_{D} = 22A$	11	-	-	S
Q <sub>g(TOT)</sub>	Total Gate Charge at 10V	V <sub>GS</sub> = 10V,	-	90	108	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DS</sub> = 400V,	-	24	29	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	I <sub>D</sub> = 44A	-	31	37	nC
t <sub>d(ON)</sub>	Turn-On Delay Time	$V_{DD} = 250V$	-	16	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> = 44A,	-	84	-	ns
t <sub>d(OFF)</sub>	Turn-Off Delay Time	$R_G = 2.15\Omega$	-	45	-	ns
t <sub>f</sub>	Fall Time	$R_D = 5.68\Omega$	-	79	-	ns
C <sub>ISS</sub>	Input Capacitance	V 25V V 20V	-	5335	-	pF
C <sub>OSS</sub>	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $V_{DS} = 1MHz$	-	645	-	pF
$C_{RSS}$	Reverse Transfer Capacitance		-	40	-	pF

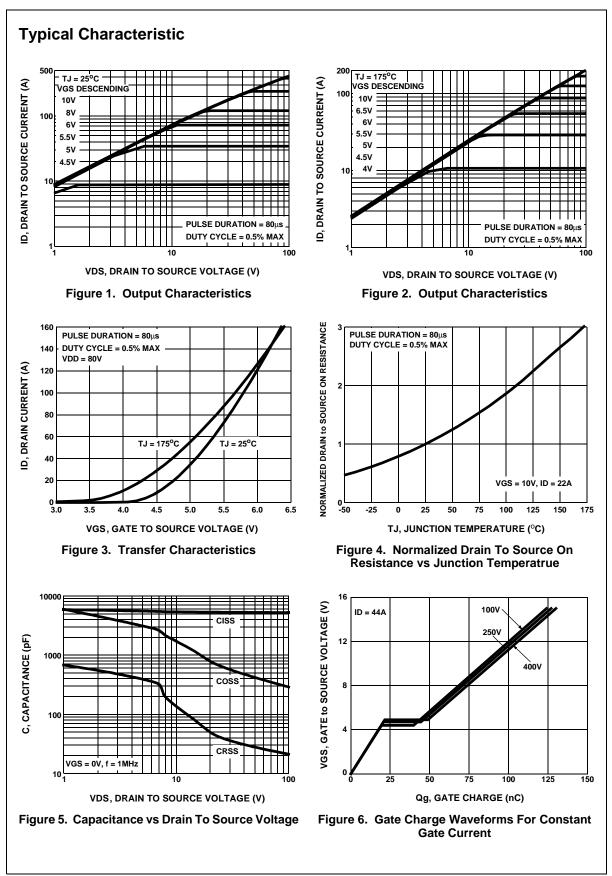
## **Avalanche Characteristics**

E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>2</sup>	1500	-	-	mJ
I <sub>AR</sub>	Avalanche Current	-	-	44	Α

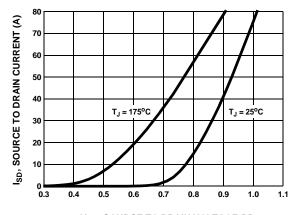
## **Drain-Source Diode Characteristics**

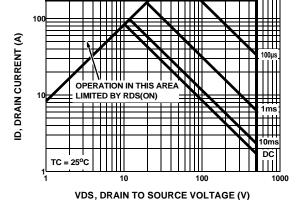
I <sub>S</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse	-	-	44	А
I <sub>SM</sub>	Pulsed Source Current <sup>1</sup> (Body Diode)	integral reverse p-n junction diode.	-	-	176	А
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 44A	-	0.900	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 44A$ , $dI_{SD}/dt = 100A/\mu s$	-	920	1100	ns
$Q_{RR}$	Reverse Recovered Charge	$I_{SD} = 44A$ , $dI_{SD}/dt = 100A/\mu s$	-	14	18	μC

1: Repetitive rating; pulse width limited by maximum junction temperature 2: Starting  $T_J$  = 25°C, L = 1.61mH,  $I_{AS}$  = 44



# Typical Characteristic (Continued)





 $V_{SD}$ , SOURCE TO DRAIN VOLTAGE (V)

Figure 7. Body Diode Forward Voltage vs Body Diode Current

Figure 8. Maximum Safe Operating Area

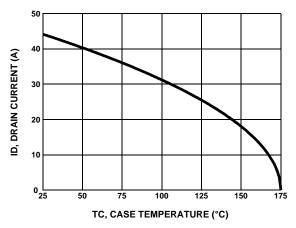
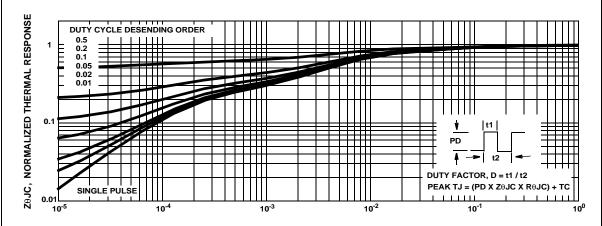


Figure 9. Maximum Drain Current vs Case Temperature



t1, RECTANGULAR PULSE DURATION (S)

Figure 10. Normalized Transient Thermal Impedance, Junction to Case

# **Test Circuits and Waveforms**

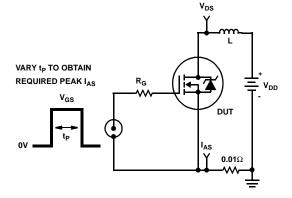


Figure 11. Unclamped Energy Test Circuit

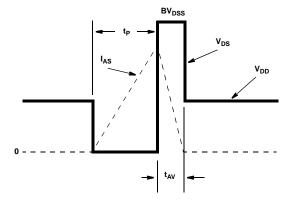


Figure 12. Unclamped Energy Waveforms

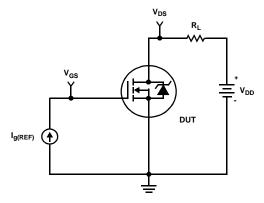


Figure 13. Gate Charge Test Circuit

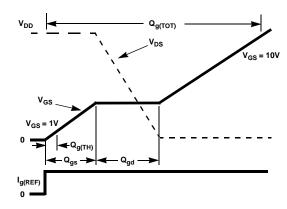


Figure 14. Gate Charge Waveforms

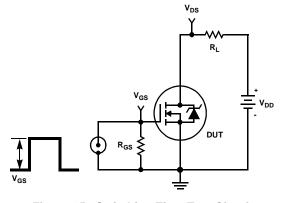


Figure 15. Switching Time Test Circuit

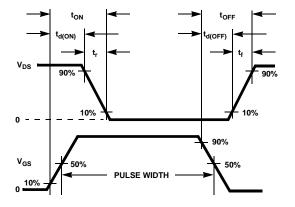


Figure 16. Switching Time Waveform

©2002 Fairchild Semiconductor Corporation

#### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ FAC	CT™	ImpliedDisconnect™	PACMAN™	SPM™
ActiveArray™ FA0		ISOPLANAR™	POP™	Stealth™
Bottomless™ FAS	ST®	LittleFET™	Power247™	SuperSOT™-3
CoolFET™ FAS	STr™	MicroFET™	PowerTrench®	SuperSOT™-6
CROSSVOLT™ FRE	FET™	MicroPak™	QFET™	SuperSOT™-8
DOME™ Glo	obalOptoisolator™	MICROWIRE™	QS™	SyncFET™
		MSX™	QT Optoelectronics™	TinyLogic™
E <sup>2</sup> CMOS™ HiS	SeC™	MSXPro™	Quiet Series™	TruTranslation™
EnSigna™ l²C™	ТМ	OCX™	RapidConfigure™	UHC™
Across the board. Aro	ound the world.™	OCXPro™	RapidConnect™	UltraFET <sup>®</sup>
The Power Franchise	тм	OPTOLOGIC®	SILENT SWITCHER®	VCX™
Programmable Active	Droop™	OPTOPLANAR™	SMART START™	

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I1